



BSC084P03NS3 G

## OptiMOS™ P3 Power-Transistor

## Features

- single P-Channel in SuperSO8
- Qualified according JEDEC<sup>1)</sup> for target applications
- 150 °C operating temperature
- 100% Avalanche tested
- $V_{GS}=25$  V, specially suited for notebook applications
- Pb-free; RoHS compliant
- applications: battery management, load switching
- Halogen-free according to IEC61249-2-21

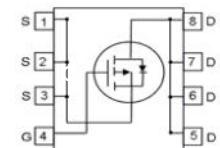
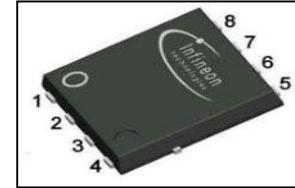


Halogen-Free

## Product Summary

$V_{DS}$	-30	V
$R_{DS(on),max}$	8.4	$m\Omega$
$I_D$	-78.6	A

PG-TDSON-8



Type	Package	Marking	Lead free	Halogen free	Packing
BSC084P03NS3 G	PG-TDSON-8	084P3NS	Yes	Yes	non dry

Maximum ratings, at  $T_j=25$  °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	$I_D$	$T_C=25$ °C	-78.6	A
		$T_C=70$ °C	-62.9	
		$T_A=25$ °C	-14.9	
Pulsed drain current	$I_{D,pulse}$	$T_C=25$ °C <sup>3)</sup>	-200	
Avalanche energy, single pulse	$E_{AS}$	$I_D=-50$ A, $R_{GS}=25$ Ω	105	mJ
Gate source voltage	$V_{GS}$		±25	V
Power dissipation	$P_{tot}$	$T_C=25$ °C	69	W
		$T_A=25$ °C <sup>2)</sup>	2.5	
Operating and storage temperature	$T_j, T_{stg}$		-55 ... 150	°C
ESD class		JESD22-A114 HBM	1C (1-2 kV)	
Soldering temperature			260	°C
IEC climatic category; DIN IEC 68-1			55/150/56	

<sup>1)</sup> J-STD20 and JESD22

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	

**Thermal characteristics**

Thermal resistance, junction - case	$R_{thJC}$		-	-	1.8	K/W
Thermal resistance, junction - ambient	$R_{thJA}$	6 cm <sup>2</sup> cooling area <sup>2)</sup>	-	-	50	

**Electrical characteristics**, at  $T_j=25$  °C, unless otherwise specified

**Static characteristics**

Drain-source breakdown voltage	$V_{(BR)DSS}$	$V_{GS}=0$ V, $I_D=-250\mu A$	-30	-	-	V
Gate threshold voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}$ , $I_D=-105 \mu A$	-3.1	-2.5	-1.9	
Zero gate voltage drain current	$I_{DSS}$	$V_{DS}=-30$ V, $V_{GS}=0$ V, $T_j=25$ °C	-	-	-1	μA
		$V_{DS}=-30$ V, $V_{GS}=0$ V, $T_j=125$ °C	-	-	-100	
Gate-source leakage current	$I_{GSS}$	$V_{GS}=-25$ V, $V_{DS}=0$ V	-	-	-100	nA
Drain-source on-state resistance	$R_{DS(on)}$	$V_{GS}=-6$ V, $I_D=-30$ A	-	8.4	14.0	mΩ
		$V_{GS}=-10$ V, $I_D=-50$ A	-	6.1	8.4	
Gate resistance	$R_G$		-	2.2	-	Ω
Transconductance	$g_{fs}$	$ V_{DS} >2 I_D R_{DS(on)max},$ $I_D=-50$ A	33	66	-	s

<sup>2)</sup> Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm<sup>2</sup> (one layer, 70 μm thick) copper area for drain connection. PCB is vertical in still air.

<sup>3)</sup> See Fig. 3



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Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	

**Dynamic characteristics**

Input capacitance	$C_{iss}$	$V_{GS}=0 \text{ V}, V_{DS}=-15 \text{ V}, f=1 \text{ MHz}$	-	3190	4785	pF
Output capacitance	$C_{oss}$		-	1520	2280	
Reverse transfer capacitance	$C_{rss}$		-	110	165	
Turn-on delay time	$t_{d(on)}$	$V_{DD}=-15 \text{ V}, V_{GS}=-10 \text{ V}, I_D=-50 \text{ A}, R_G=6 \Omega$	-	16	25	ns
Rise time	$t_r$		-	134	200	
Turn-off delay time	$t_{d(off)}$		-	33	50	
Fall time	$t_f$		-	8	12	

**Gate Charge Characteristics<sup>3)</sup>**

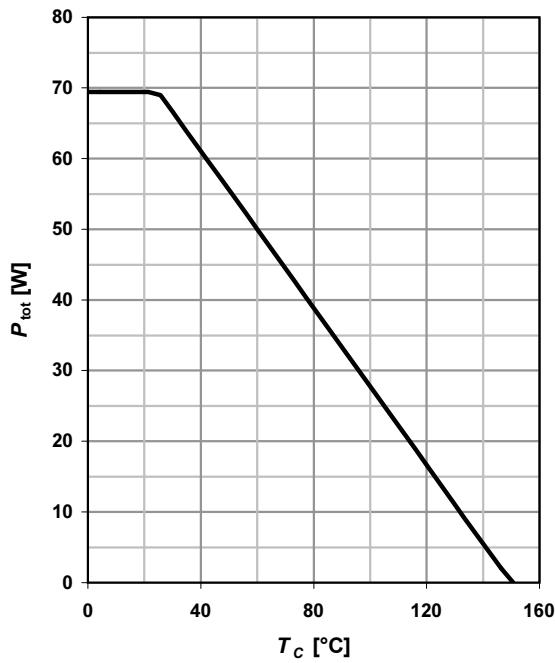
Gate to source charge	$Q_{gs}$	$V_{DD}=-15 \text{ V}, I_D=-50 \text{ A}, V_{GS}=0 \text{ to } -10 \text{ V}$	-	15	20	nC
Gate charge at threshold	$Q_{g(th)}$		-	5	7	
Gate to drain charge	$Q_{gd}$		-	7	11	
Switching charge	$Q_{sw}$		-	17	24	
Gate charge total	$Q_g$		-	43	58	
Gate plateau voltage	$V_{plateau}$		-	4.7	-	V
Output charge	$Q_{oss}$	$V_{DD}=-15 \text{ V}, V_{GS}=0 \text{ V}$	-	35	46	nC

**Reverse Diode**

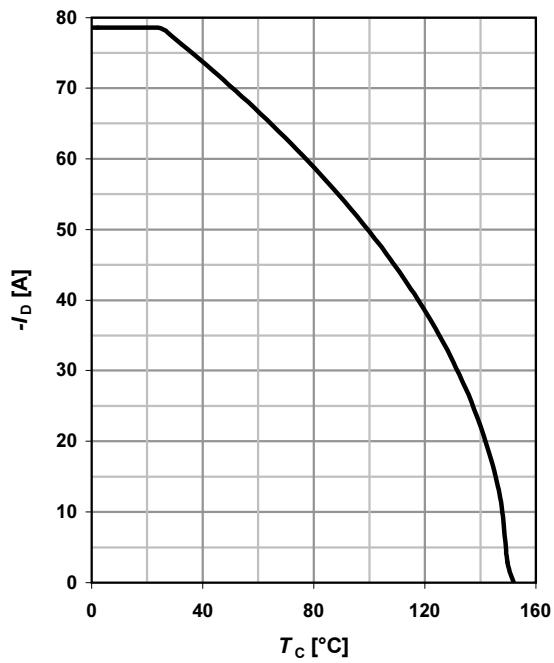
Diode continuous forward current	$I_s$	$T_c=25 \text{ }^\circ\text{C}$	-	-	78	A
Diode pulse current	$I_{s,pulse}$		-	-	200	
Diode forward voltage	$V_{SD}$	$V_{GS}=0 \text{ V}, I_F=-50 \text{ A}, T_j=25 \text{ }^\circ\text{C}$	-	-	-1.1	V
Reverse recovery time	$t_{rr}$	$V_R=15 \text{ V}, I_F= I_s , dI_F/dt=100 \text{ A}/\mu\text{s}$	-	45	-	ns
Reverse recovery charge	$Q_{rr}$		-	50	-	

**1 Power dissipation**

$$P_{\text{tot}} = f(T_c)$$

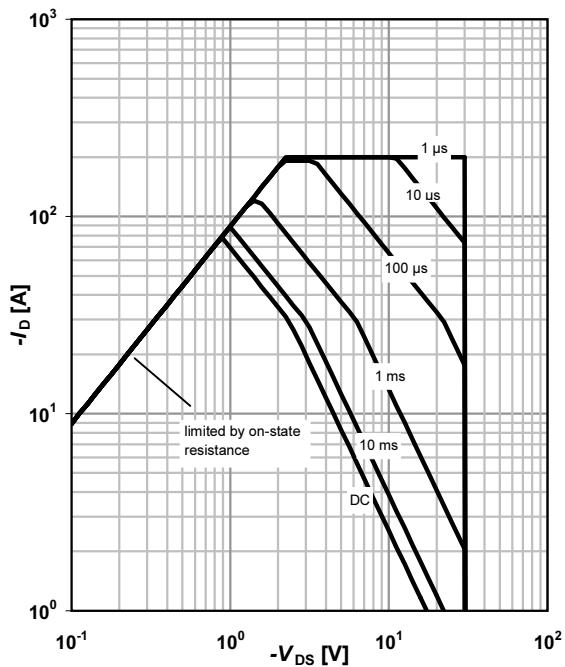

**2 Drain current**

$$I_D = f(T_c); |V_{GS}| \geq 10 \text{ V}$$


**3 Safe operating area**

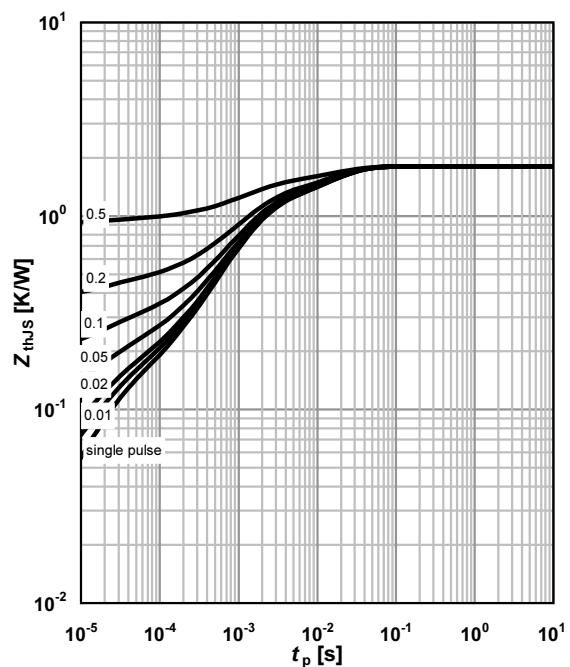
$$I_D = f(V_{DS}); T_c = 25 \text{ °C}^1); D = 0$$

parameter:  $t_p$


**4 Max. transient thermal impedance**

$$Z_{\text{thJS}} = f(t_p)$$

parameter:  $D = t_p/T$



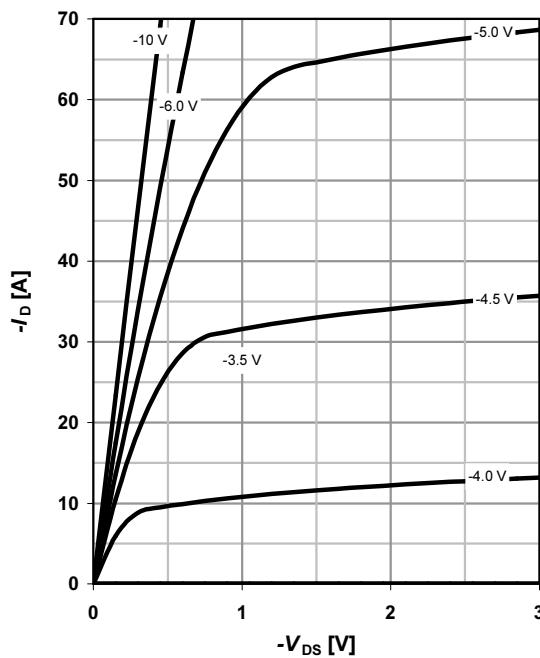


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### 5 Typ. output characteristics

$I_D=f(V_{DS})$ ;  $T_j=25\text{ }^\circ\text{C}$

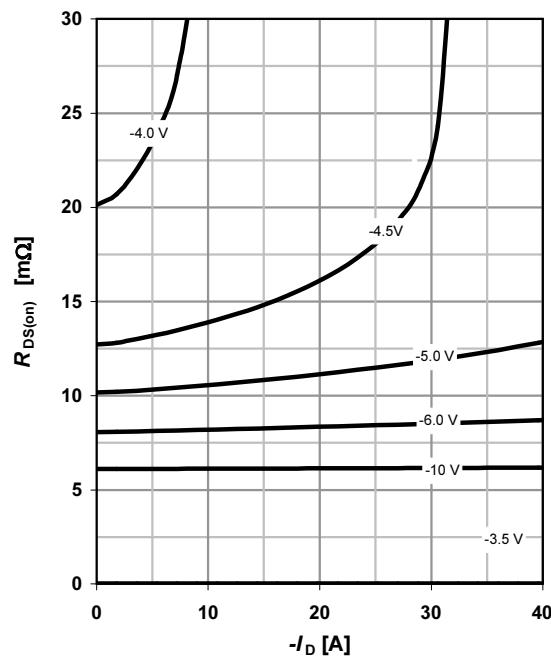
parameter:  $V_{GS}$



### 6 Typ. drain-source on resistance

$R_{DS(on)}=f(I_D)$ ;  $T_j=25\text{ }^\circ\text{C}$

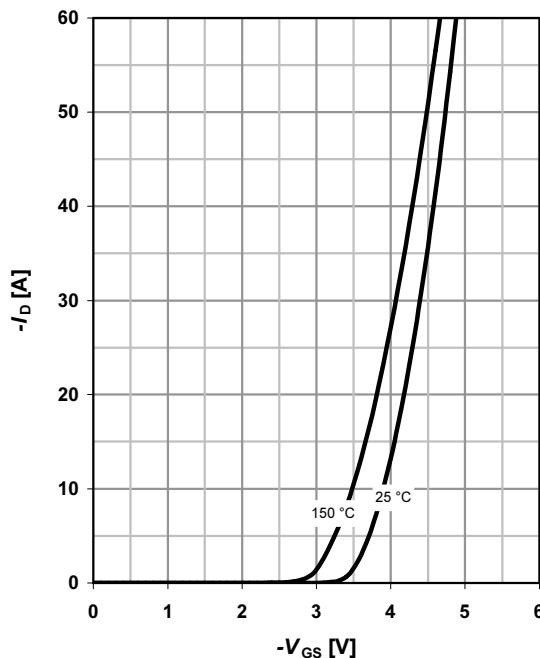
parameter:  $V_{GS}$



### 7 Typ. transfer characteristics

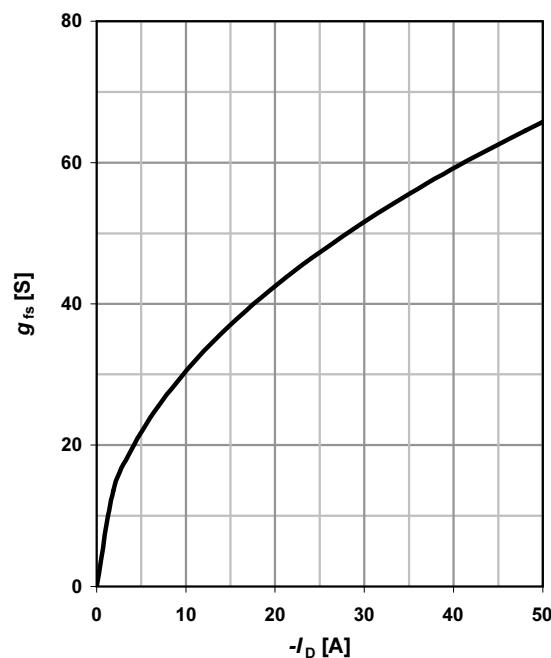
$I_D=f(V_{GS})$ ;  $|V_{DS}|>2|I_D|R_{DS(on)max}$

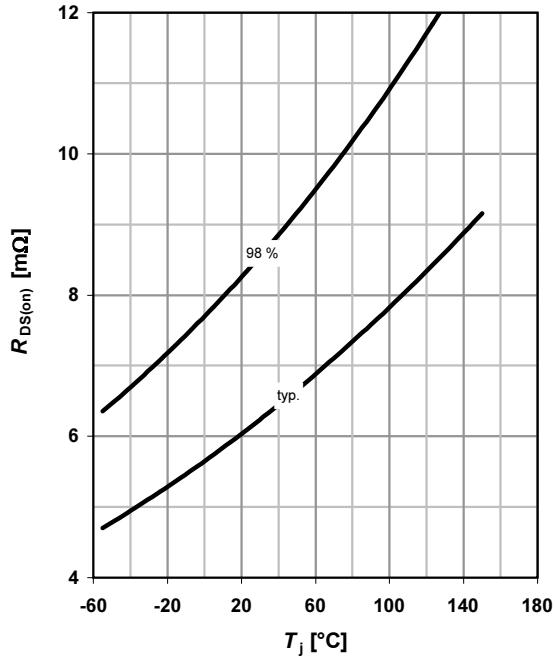
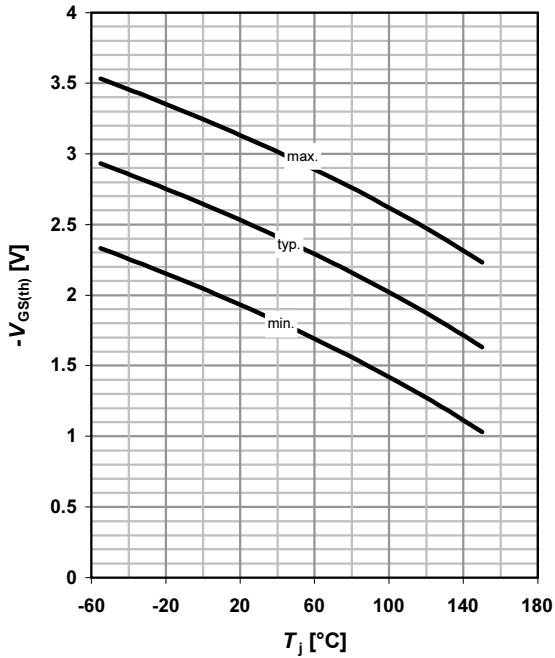
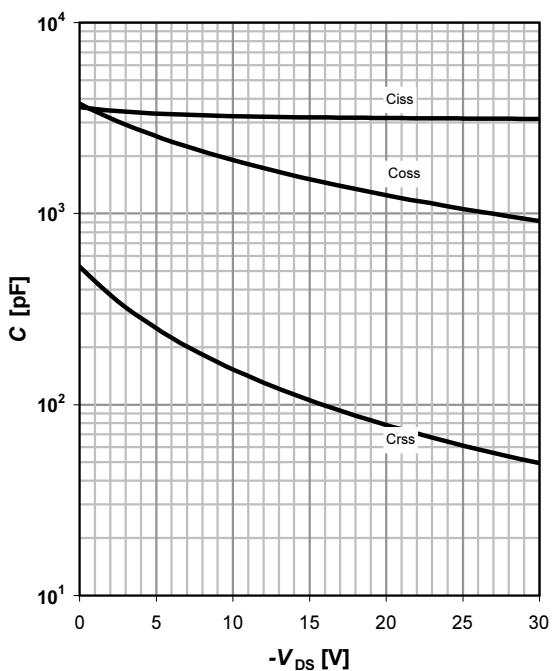
parameter:  $T_j$

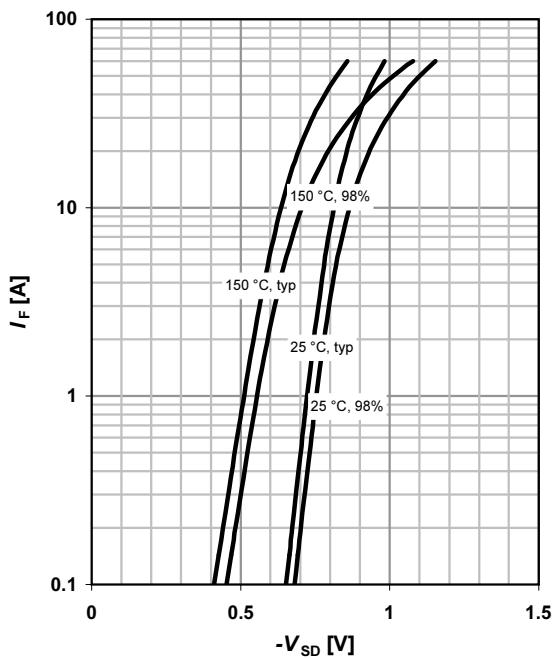


### 8 Typ. forward transconductance

$g_{fs}=f(I_D)$ ;  $T_j=25\text{ }^\circ\text{C}$



**9 Drain-source on-state resistance**
 $R_{DS(on)} = f(T_j); I_D = -30 \text{ A}; V_{GS} = -10 \text{ V}$ 

**10 Typ. gate threshold voltage**
 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}; I_D = -105 \mu\text{A}$ 

**11 Typ. capacitances**
 $C = f(V_{DS}); V_{GS} = 0 \text{ V}; f = 1 \text{ MHz}$ 

**12 Forward characteristics of reverse diode**
 $I_F = f(V_{SD})$ 

 parameter:  $T_j$ 


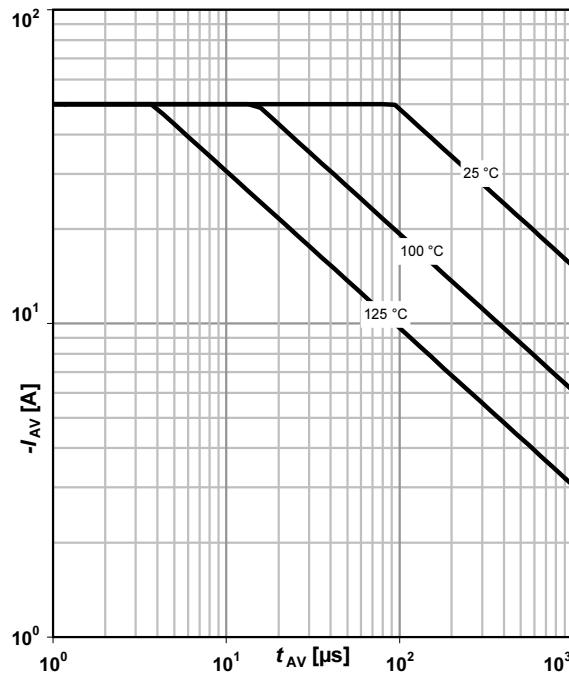


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**13 Avalanche characteristics**

$I_{AS}=f(t_{AV})$ ;  $R_{GS}=25 \Omega$

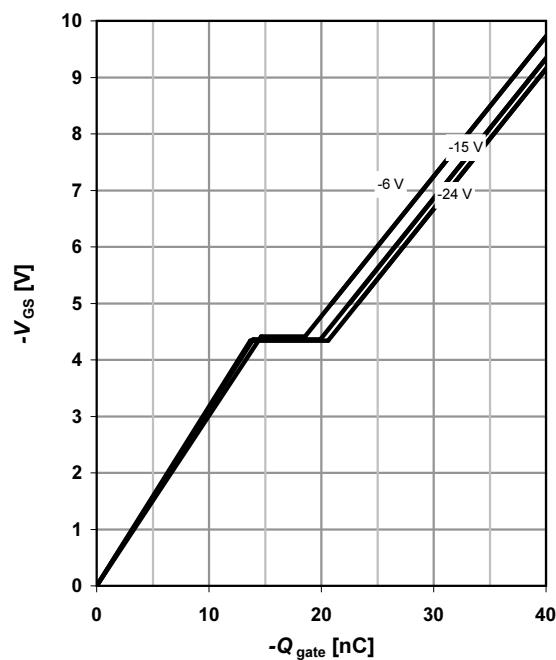
parameter:  $T_{j(start)}$



**14 Typ. gate charge**

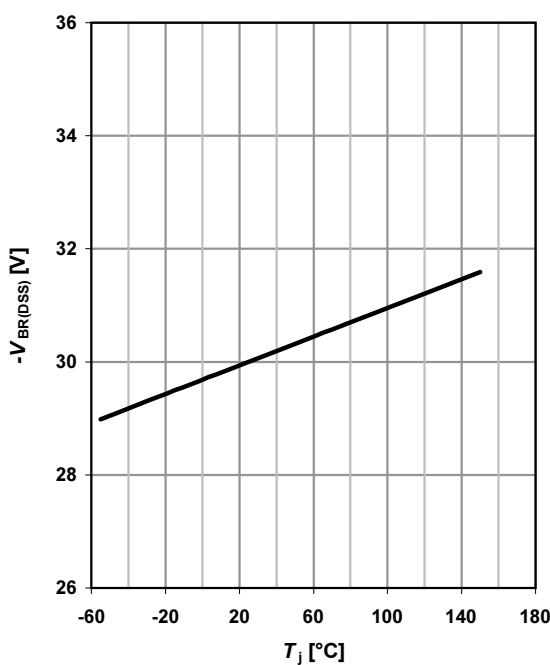
$V_{GS}=f(Q_{gate})$ ;  $I_D=-50$  A pulsed

parameter:  $V_{DD}$

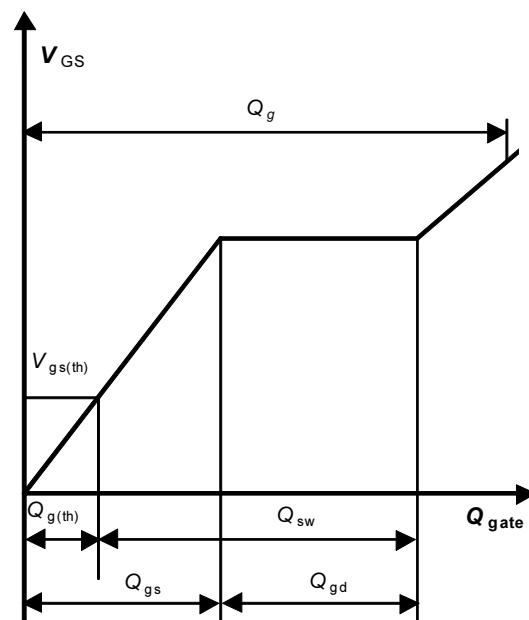


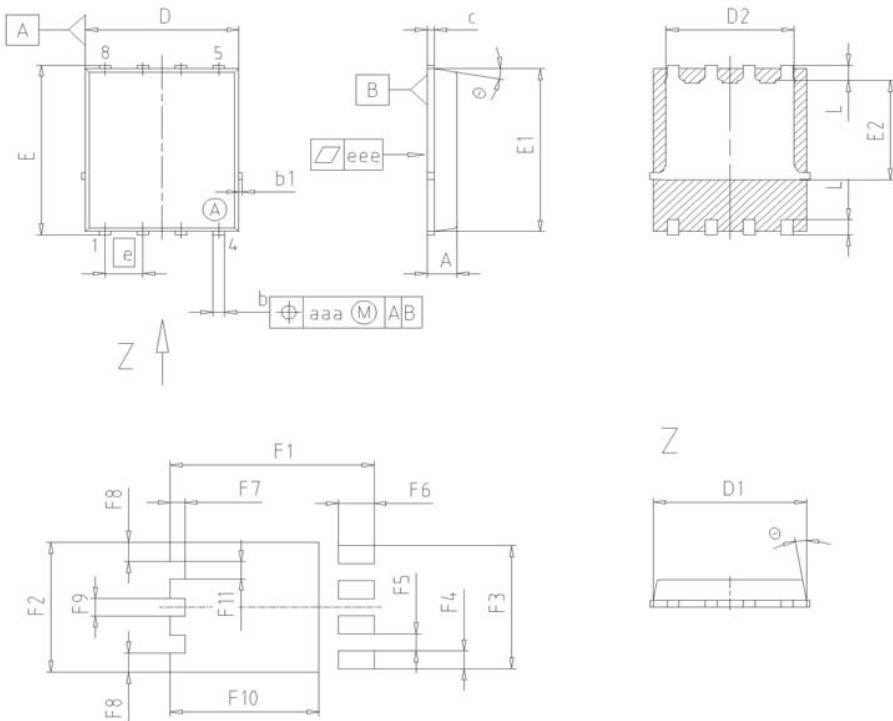
**15 Drain-source breakdown voltage**

$V_{BR(DSS)}=f(T_j)$ ;  $I_D=-250 \mu A$



**16 Gate charge waveforms**



**Package Outline**
**PG-TDS0N-8**


DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
<b>A</b>	0.90	1.10	0.035	0.043
<b>b</b>	0.34	0.54	0.013	0.021
<b>b1</b>	0.02	0.22	0.001	0.008
<b>c</b>	0.15	0.35	0.006	0.014
<b>D=D1</b>	4.95	5.35	0.195	0.211
<b>D2</b>	4.20	4.40	0.165	0.173
<b>E</b>	5.95	6.35	0.234	0.250
<b>E1</b>	5.70	6.10	0.224	0.240
<b>E2</b>	3.40	3.80	0.134	0.150
<b>e</b>	1.27		0.050	
<b>N</b>	8		8	
<b>L</b>	0.45	0.65	0.018	0.026
$\square$	8.5°	11.5°	8.5°	11.5°
<b>aaa</b>	0.25		0.010	
<b>eee</b>	0.05		0.002	
<b>F1</b>	6.75	6.95	0.266	0.274
<b>F2</b>	4.60	4.80	0.181	0.189
<b>F3</b>	4.36	4.56	0.172	0.180
<b>F4</b>	0.55	0.75	0.022	0.030
<b>F5</b>	0.52	0.72	0.020	0.028
<b>F6</b>	1.10	1.30	0.043	0.051
<b>F7</b>	0.40	0.60	0.016	0.024
<b>F8</b>	0.60	0.80	0.024	0.031
<b>F9</b>	0.53	0.73	0.021	0.029
<b>F10</b>	4.90	5.10	0.193	0.201
<b>F11</b>	0.53	0.73	0.021	0.029

<b>DOCUMENT NO.</b>
Z8B00003332
<b>SCALE</b>
0      2.5      5mm
<b>EUROPEAN PROJECTION</b>
<b>ISSUE DATE</b>
08-03-2007
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03

Dimensions in mm



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